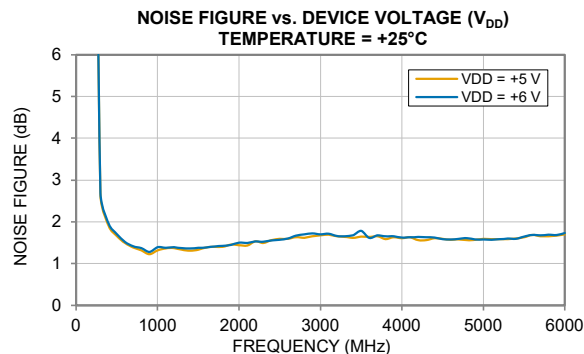
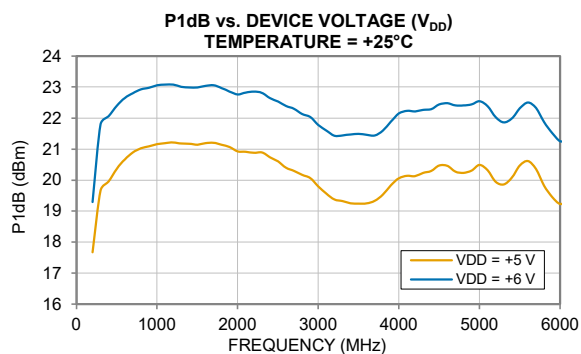
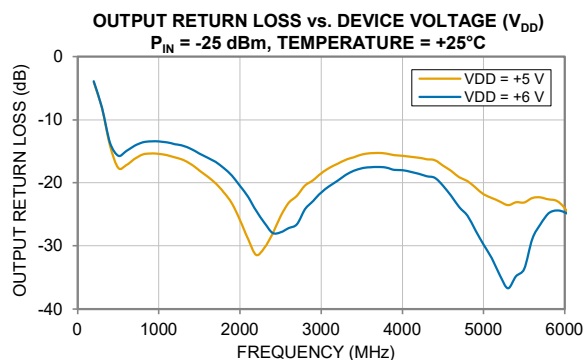
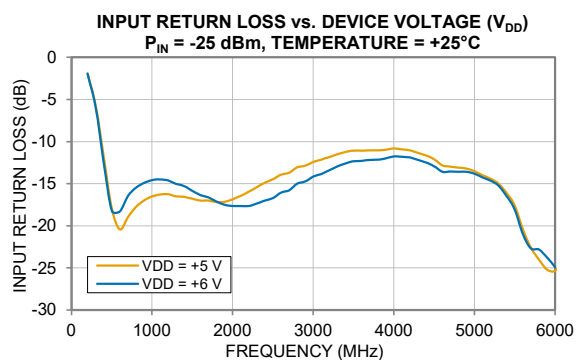
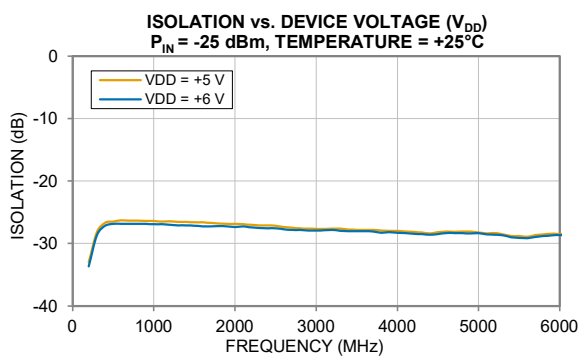
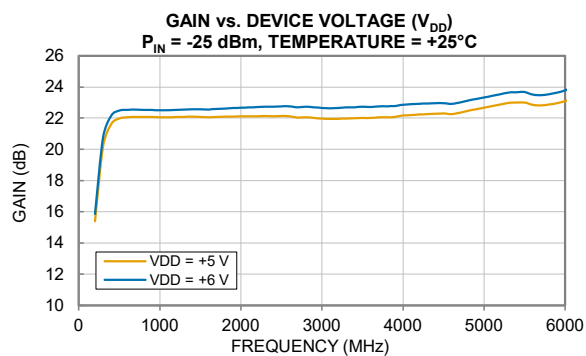


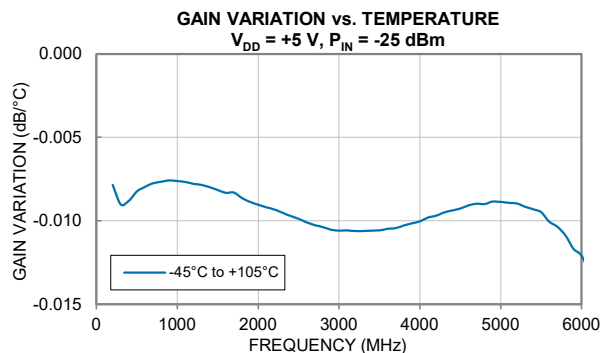
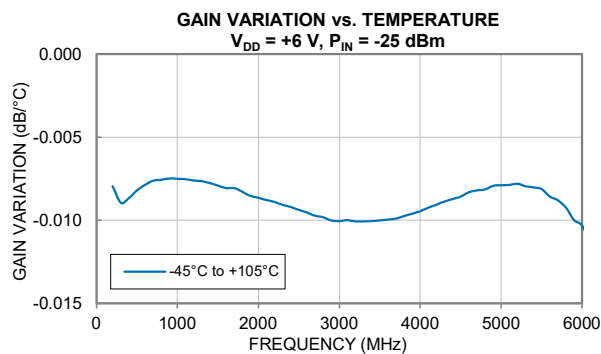
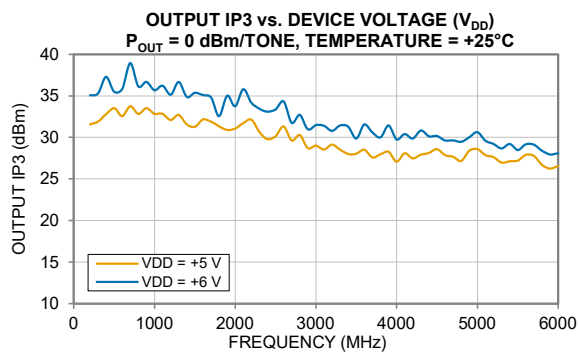
Typical Performance Curves

Note: The following data was taken on the Mini-Circuits Die Characterization 400-6000 MHz Test Board (Figure 3). All data taken at nominal conditions $V_{EN} = V_{DD}$ and $R_{I_{ADJ}} = \text{Open}$ unless noted otherwise. For additional over temperature graphs, see TSY-83LN+.



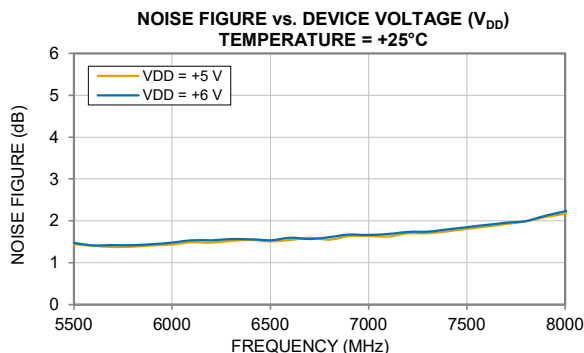
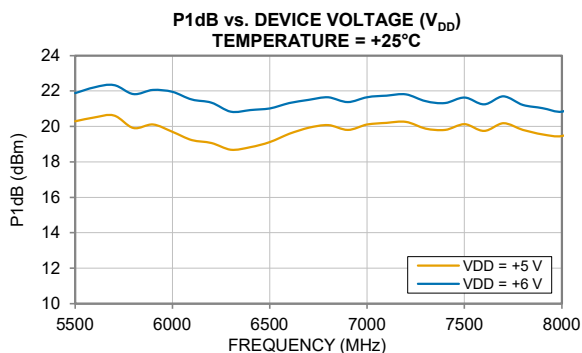
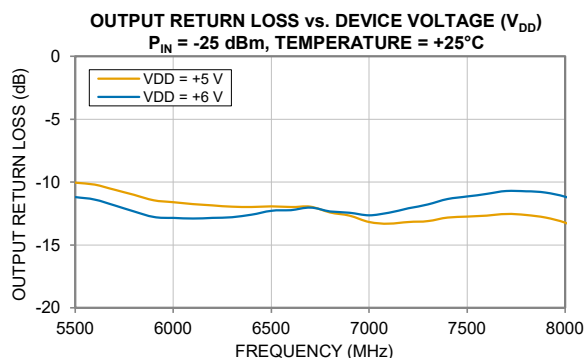
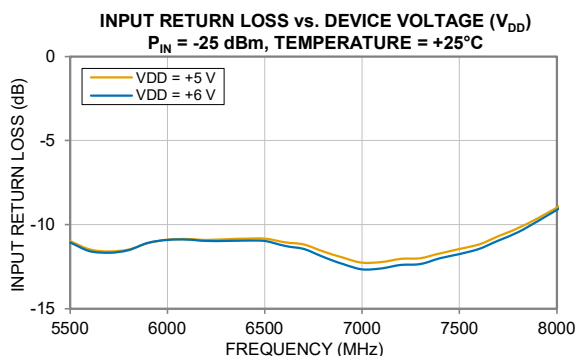
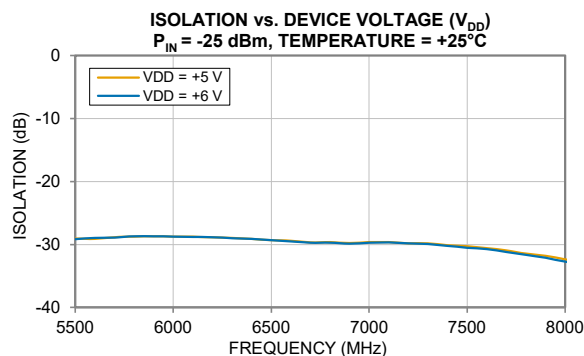
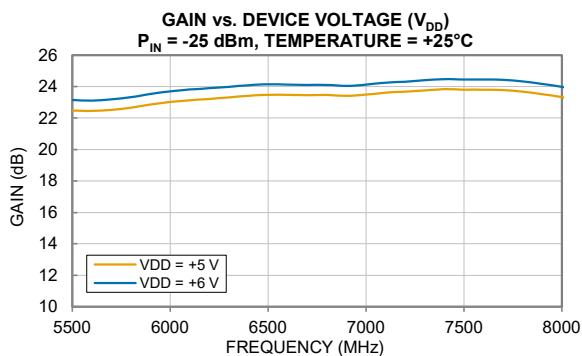
Typical Performance Curves

Note: The following data was taken on the Mini-Circuits Die Characterization 400-6000 MHz Test Board (Figure 3). All data taken at nominal conditions $V_{EN} = V_{DD}$ and RI_{ADJ} = Open unless noted otherwise. For additional graphs over temperature, see TSY-83LN+.



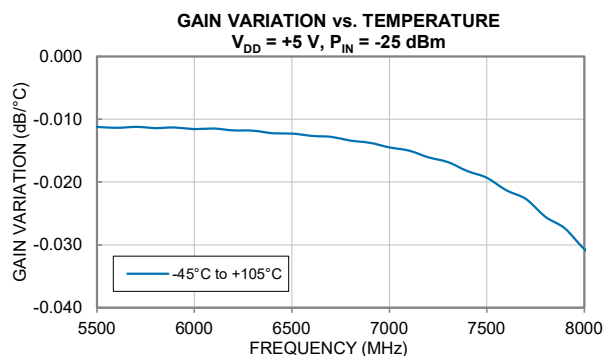
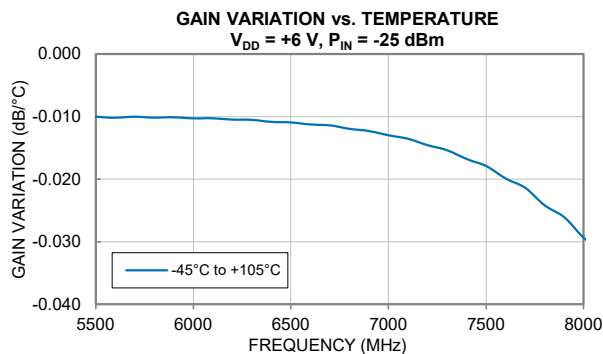
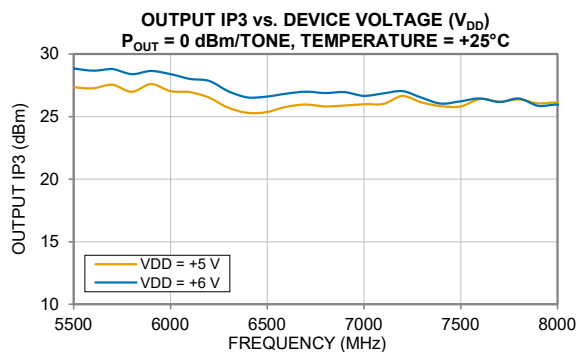
Typical Performance Curves

Note: The following data was taken on the Mini-Circuits Die Characterization 5500-8000 MHz Test Board (Figure 4). All data taken at nominal conditions $V_{EN} = V_{DD}$ and $R_{IADJ} = \text{Open}$ unless noted otherwise. For additional graphs over temperature, see TSY-83LN+.



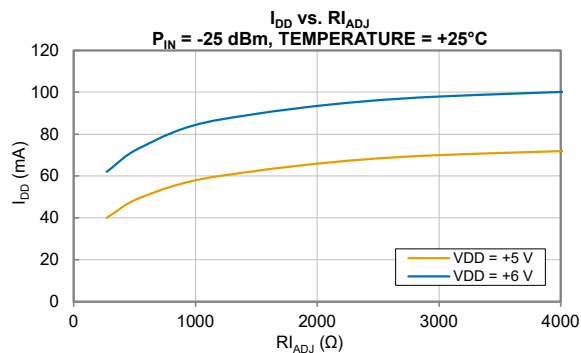
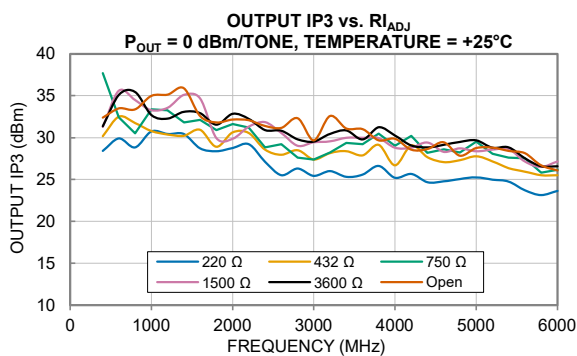
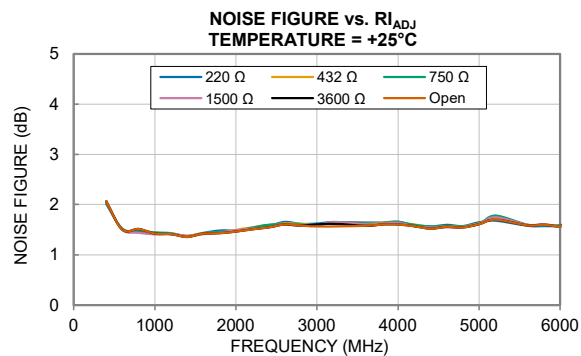
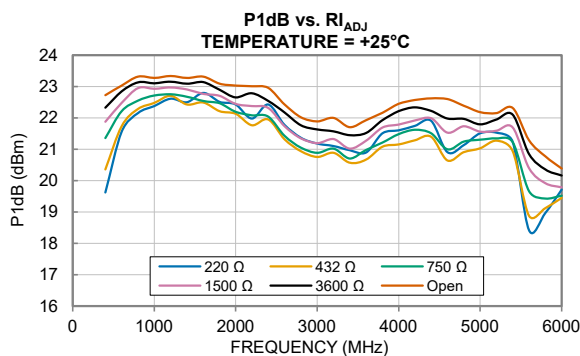
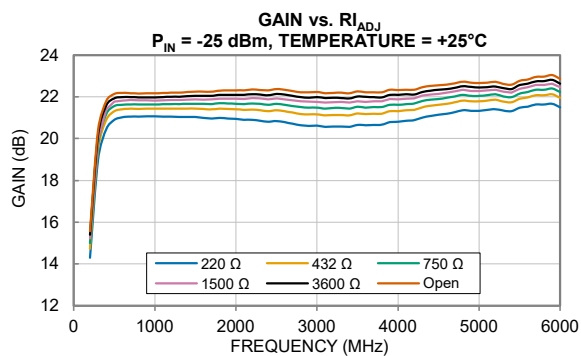
Typical Performance Curves

Note: The following data was taken on the Mini-Circuits Die Characterization 5500-8000 MHz Test Board (Figure 4). All data taken at nominal conditions $V_{EN} = V_{DD}$ and $R_{I_{ADJ}} = \text{Open}$ unless noted otherwise. For additional graphs over temperature, see TSY-83LN+.



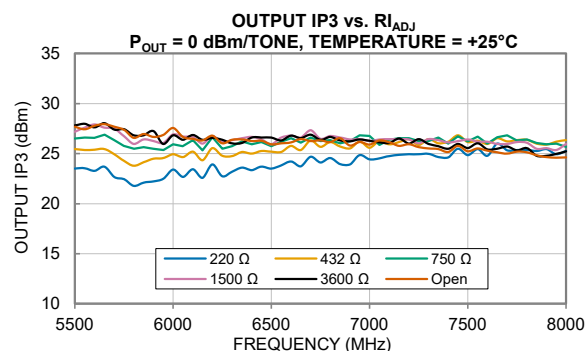
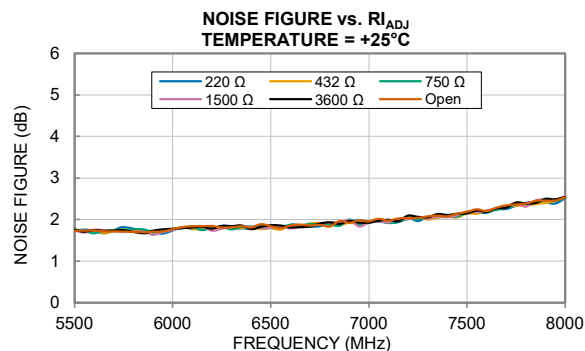
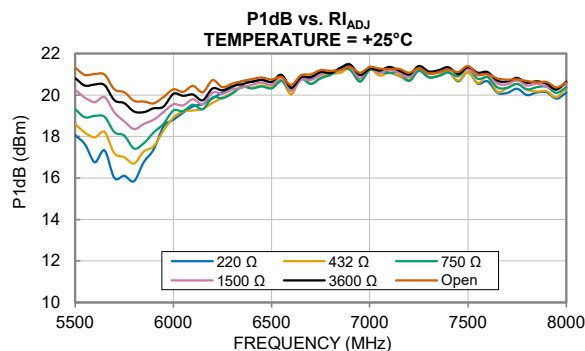
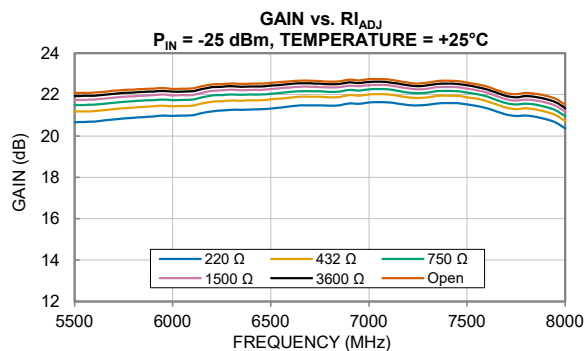
Typical Performance Curves

Note: The following data was taken of the packaged TSY-83LN+ mounted on Mini-Circuits Characterization Test Board TB-TSY-83LNC+ (see Figure 3). All data taken at nominal conditions $V_{EN} = V_{DD} = +6$ V unless noted otherwise. For additional graphs over temperature, see TSY-83LN+.



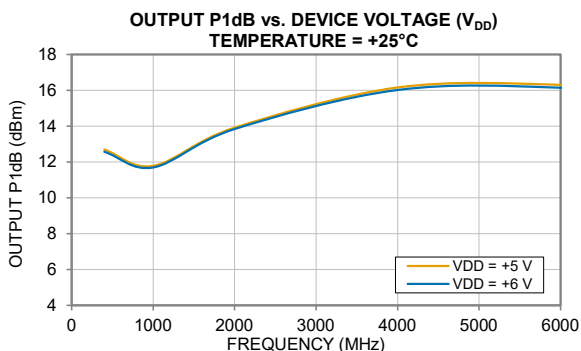
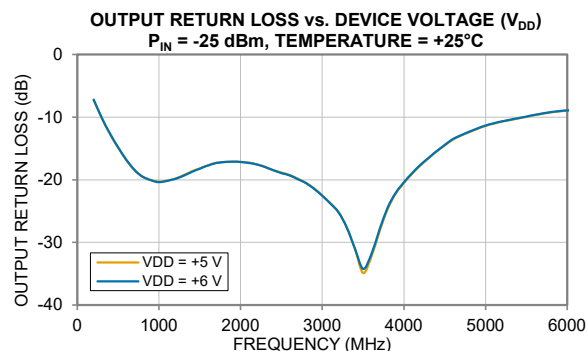
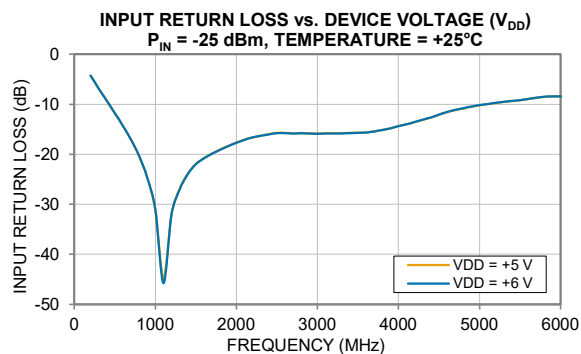
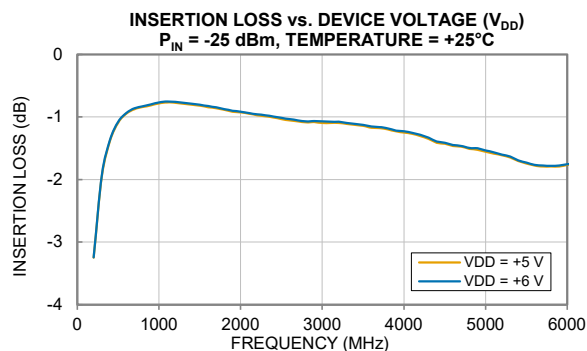
Typical Performance Curves

Note: The following data was taken of the packaged TSY-83LN+ mounted on Mini-Circuits Characterization Test Board TB-TSY-832LNC+ (Figure 4). All data taken at nominal conditions $V_{EN} = V_{DD} = +6$ V unless noted otherwise. For additional graphs over temperature, see TSY-83LN+.



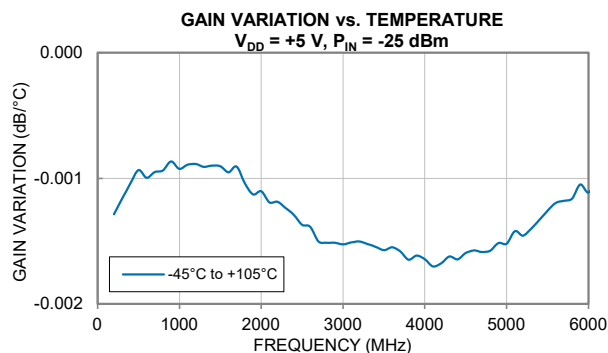
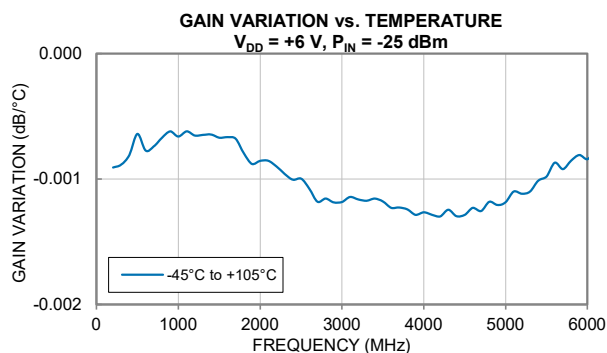
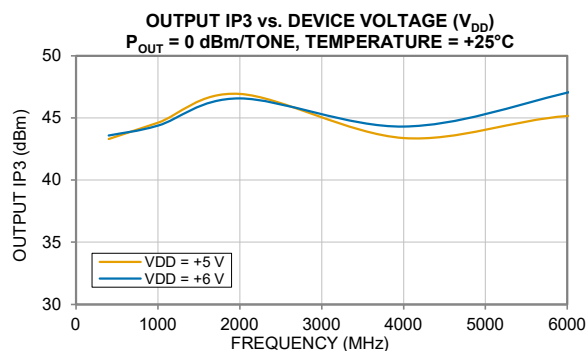
Typical Performance Curves

Note: The following data was taken on Mini-Circuits Die Characterization 400-6000 MHz Test Board (Figure 3). All data taken at nominal conditions $V_{EN} = 0$ V and $R_{I_{ADJ}} = \text{Open}$ unless noted otherwise. For additional graphs over temperature, see TSY-83LN+.



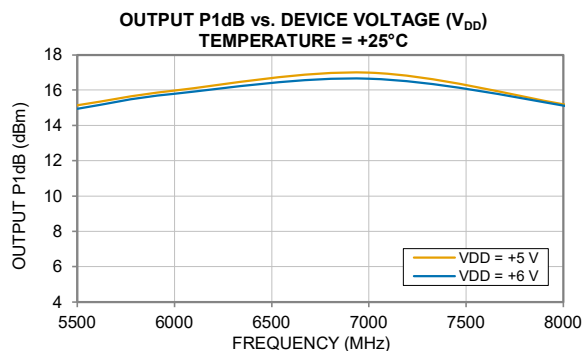
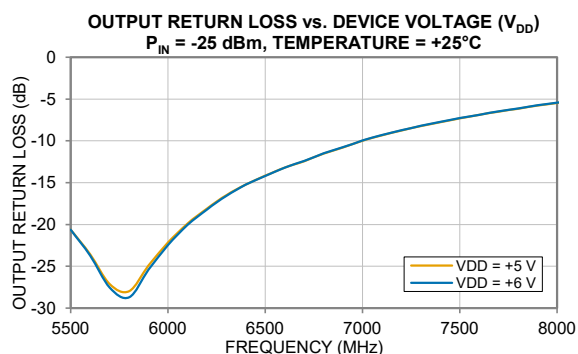
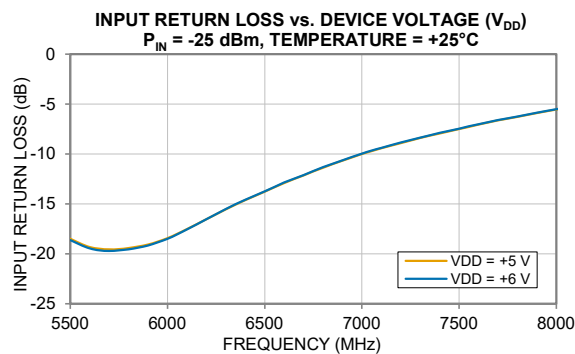
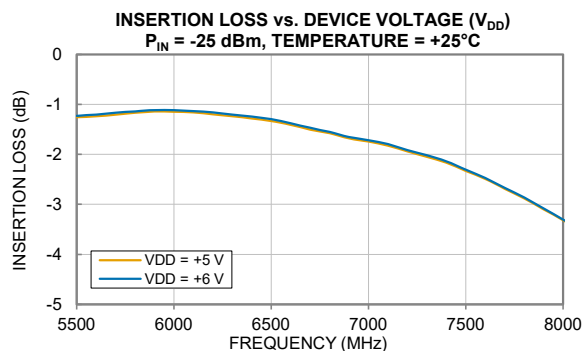
Typical Performance Curves

Note: The following data was taken on Mini-Circuits Die Characterization 400-6000 MHz Test Board (Figure 3). All data taken at nominal conditions $V_{EN} = 0$ V and $R_{IADJ} = \text{Open}$ unless noted otherwise. For additional graphs over temperature, see TSY-83LN+.



Typical Performance Curves

Note: The following data was taken on Mini-Circuits Die Characterization 5500-8000 MHz Test Board (Figure 4). All data taken at nominal conditions $V_{EN} = 0$ V and $RI_{ADJ} = \text{Open}$ unless noted otherwise. For additional graphs over temperature, see TSY-83LN+.



Typical Performance Curves

Note: The following data was taken on Mini-Circuits Die Characterization 5500-8000 MHz Test Board (Figure 4). All data taken at nominal conditions $V_{EN} = 0$ V and $R_{I_{ADJ}} = \text{Open}$ unless noted otherwise. For additional graphs over temperature, see TSY-83LN+.

